

Experimental Evaluation of Reset Control for Improved Stage Performance

M.F. Heertjes ^{*,**} K.G.J. Gruntjens ^{***} S.J.L.M. van Loon ^{**}
N. van de Wouw ^{**,****,†} W.P.M.H. Heemels ^{**}

^{*} *ASML, Mechatronic Systems Development, Veldhoven, The Netherlands and Eindhoven University of Technology, Mechanical Engineering, Eindhoven, The Netherlands.*
(marcel.heertjes@asml.com)

^{**} *Eindhoven University of Technology, Mechanical Engineering, Eindhoven, The Netherlands.*

^{***} *Océ Technologies, Mechanical Department, Venlo, The Netherlands.*

^{****} *Department of Civil, Environmental and Geo-Engineering, University of Minnesota, Minneapolis, MN 55455 USA.*

[†] *Delft Center for Systems and Control, Delft University of Technology, Delft, The Netherlands.*

Abstract: A reset integral controller is discussed that induces improved low-frequency disturbance rejection properties under double integrator control without giving the unwanted increase of overshoot otherwise resulting from adding an extra linear integrator. To guarantee closed-loop stability, a (conditional) reset condition is used that restricts the input-output behavior of the dynamic reset element to a $[0, \alpha]$ -sector with α a positive (finite) gain. As a result, stability can be guaranteed on the basis of a circle criterion-like argument and checked through (measured) frequency response data. Both stability and performance of the control design will be discussed via measurement results obtained from a wafer stage system of an industrial wafer scanner.

© 2016, IFAC (International Federation of Automatic Control) Hosting by Elsevier Ltd. All rights reserved.

Keywords: Circle criterion, Lyapunov stability, motion systems, reset control, wafer scanners.

1. INTRODUCTION

This paper discusses a reset integral controller design to cope with the conventional trade-off between a) improved low-frequency disturbance suppression through integral control and b) desired transient response, which in view of the mentioned integral control usually deteriorates. This trade-off generically arises in high-precision motion control applications like for example wafer scanners, which are used in the production of chips, and which require nanometer accuracies under aggressive motion profiles; for the control of wafer scanners see also (Butler, 2011).

Nonlinear control has been opted by many researchers (Seron & Goodwin, 1996) in an attempt to balance the above-mentioned trade-off in a more desirable manner. An interesting concept in this regard is reset control, see for example the Clegg integrator that later developed into first-order reset elements (FORE), see Clegg (1958); Horowitz & Rosenbaum (1975); Zaccarian et al. (2005). The Clegg integrator is a simple integrator that resets its state to zero upon zero input crossings. Its describing function possesses a 20 dB/decade amplitude decay with 38.15 degrees of phase lag instead of the 90 degrees phase lag corresponding to a linear integrator (Clegg, 1958).

With these advantages in mind, recently a variable-gain integrator with reset properties has been proposed by Heertjes et al. (2015). In this work, the variable-gain

integrator with reset combines a variable-gain integral controller with a Clegg integrator. The measurement results obtained for this type of controller applied to a piezo-actuated lens system clearly demonstrated its benefits. Stability of the closed-loop reset system essentially boils down to satisfying two conditions: i) a flow condition in the intervals between resets, and ii) a jump condition at the resets, see also Aangenent et al. (2010); Baños et al. (2011); Beker et al. (2004); Zaccarian et al. (2005, 2011); Carrasco et al. (2010). For the base-nonlinear system, i.e., the variable-gain integrator without the reset, stability has been guaranteed by the application of the positive real lemma, thereby guaranteeing satisfactory the flow condition. For the closed-loop nonlinear system with reset, a quadratic Lyapunov function candidate is found that satisfies both the flow and the jump condition. This is done by pursuing an LMI-(linear matrix inequalities) based approach. In the high-precision industry, however, using LMI-based design conditions is considered as less desirable, because it requires a parametric model of the plant to be controlled, which is often difficult to obtain and which rarely meets the requirements imposed on model accuracy. Moreover, LMI stability analysis only renders limited physical or controller tuning insights compared to frequency-domain techniques, while this is crucial in support of the development of a generically applicable controller strategy.

Download English Version:

<https://daneshyari.com/en/article/708782>

Download Persian Version:

<https://daneshyari.com/article/708782>

[Daneshyari.com](https://daneshyari.com)